S	earch N	lotes

Application/Control No.	Applicant(s)/Patent under Reexamination	_
09/779,222	COVELLI ET AL.	
Examiner	Art Unit	
Dienane M. Bayard	2141	

	SEAR	CHED	
Class	Subclass	Date	Examiner
709	238	8/17/2005	DB
709	219	8/17/2005	DB
709	203	8/17/2005	DB

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
709	238	8/17/2005	DB
709	219	8/17/2005	DB
709	203	8/17/2005	DB

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East	8/18/2008	DB
NPL search (google, IEEE)	8/18/2005	DB
EIC (NPL and patent literature search)	8/18/2005	DB
Consulted with Z. Maung	8/18/2005	DB
Consulted with M. Meky	8/18/2005	DB
Inventor's search	8/18/2005	DB